Piezoresistance in *p-Type* Gallium Antimonide*

O. N. TUFTE AND E. L. STELZER *Honeywell Research Center, Hopkins*, *Minnesota* (Received 21 October 1963)

The piezoresistance effect has been measured in p -type gallium antimonide having a hole concentration of approximately 1×10^{17} cm⁻³ over a temperature range from 77 to 350°K. At 300°K, the values of the piezoresistance coefficients π_{11} , π_{12} , and π_{44} are 5×10^{-12} , -2.4×10^{-12} , and 87×10^{-12} cm²/dyn, respectively. A germanium-type valence band structure is shown to be consistent with both the piezoresistance results and previous magnetoresistance results, whereas none of the many-valley models are consistent with both measurements.

INTRODUCTION

THE valence band structure of gallium antimonide
near the band edge is probably¹ similar to ger-
manium, but only a limited amount of experimental HE valence band structure of gallium antimonide near the band edge is probably¹ similar to gerinformation is available. The results of free carrier absorption experiments^{2,3} suggest transitions between two overlapping bands. Magnetoresistance measurements³⁻⁵ are also consistent with a germanium-type valence band, but in this case other interpretations are also possible. The problem with the interpretation of magnetoresistance results is that the low-field coefficients *B*, *C*, and *D* follow the symmetry relation $B+C$ $=-D$ for both a many-valley-type band structure with energy minima along the $[100]$ reciprocal axes⁶ and a germanium-type valence band structure.⁷ However, the magnetic field dependence of the magnetoresistance and Hall effects at lower temperatures indicates the presence of light- and heavy-mass carriers as in a germanium-type valence band. The purpose of this paper is to present the results of an investigation of the piezoresistance effect in *p-type* gallium antimonide and to use these results to distinguish between the two possible types of band structure indicated by the magnetoresistance results.

EXPERIMENTAL

Single crystals of gallium antimonide were grown by a horizontal zone leveling technique. The crystals were *p* type as grown and have a hole concentration of approximately 10¹⁷ cm⁻³. Oriented samples having sidearms for making electrical contacts were ultrasonically cut from these crystals. For the piezoresistance measurements, a tensile stress was applied to the sample by means of cords passing through the enlarged sample ends. The piezoresistance was measured using a con-

i H. Ehrenreich, J. Appl. Phys. 32, 2155 (1961).

stant current dc method. The unstrained sample voltage was balanced out on a Rubicon type B potentiometer and the output of the potentiometer connected to a dc amplifier and recorder. In this manner, the change in voltage due to the applied stress was measured on the recorder. Stresses up to 5×10^7 dyn/cm² were used in the measurements and a linear relation between the applied stress and the voltage change was found on all samples.

From a combination of longitudinal piezoresistance measurements on [100] and [111] oriented samples and transverse piezoresistance measurements on [100] oriented samples, the piezoresistance coefficients π_{11} , π_{12} , and π_{44} were evaluated. For the orientations used, the relations between the measured change in the sample resistance $\Delta R/R$ due to an applied stress χ and the piezoresistance coefficients are^{8,9}:

$$
\frac{1}{\chi} \frac{\Delta R}{R} = \frac{1}{3} \left[(\pi_{11} + 2\pi_{12}) + 2\pi_{44} \right] \n+ \frac{1}{3} \left[2S_{44} - (S_{11} + 2S_{12}) \right] \quad [111] \text{ long}, \n\frac{1}{\chi} \frac{\Delta R}{R} = \pi_{11} + (S_{11} - 2S_{12}) \quad [100] \text{ long}, \n\frac{1}{\chi} \frac{\Delta R}{R} = \pi_{12} - S_{11} \quad [100] \text{ trans.}
$$

In these equations, the S_{ij} are the elastic compliance constants which correct for the change in resistance due to dimensional changes in the crystal with stress. The elastic constants for gallium antimonide reported by McSkimin *et al.¹⁰* have been used in making these

TABLE I. Values of the resistivity, Hall coefficient, and Hall mobility of a typical gallium antimonide sample.

	$p(0 - cm)$	$R \, \text{cm}^3/\text{C}$	μ_H (cm ² /V-sec)
300° K	0.08	57	712
$77^{\circ}K$	0.12	375	3150

8 C. S. Smith, Phys. Rev. 94, 42 (1954).

^{*} A preliminary account of this work was presented at the American Physical Society Meeting, 24-25 November 1961, at the University of Chicago, Chicago, Illinois.

² A. K. Ramdas and H. Y. Fan, Bull. Am. Phys. Soc. 3, 121 (1958).

³ W. M. Becker, A. K. Ramdas, and H. Y. Fan, J. Appl. Phys.

^{32, 2094 (1961).} 4 O. N. Tufte and E. L. Stelzer, Bull. Am. Phys. Soc. 6, 426 (1901) .

s M. Matyas and J. Skacha, Chez. J. Phys. **B12,** 566 (1962). • M. Shibuya, Phys. Rev. 95, 1385 (1954). 7 J. G. Mavroides and B. Lax, Phys. Rev. **107,** 1530 (1957).

⁹ R. F. Potter and W. J. McKean, J. Res. Natl. Bur. Std. U. S.

^{59, 427 (1957).} 10 H. J. McSkimin, W. L. Bond, G. L. Pearson, and H. J. Hrostowski, Bull. Am. Phvs. Soc. 1, 111 (1956).

corrections. For the transverse measurement, an arrangement similar to Smith's⁸ method B was used. The accuracy of the π_{12} value measured by this technique is estimated to be $\pm 20\%$. The accuracy of the π_{11} and π_{44} values is $\pm 5\%$.

The electrical conductivity, Hall coefficient, and Hall mobility of a typical sample are given in Table I. The properties of all of the samples used in this investigation are very nearly identical with those given in Table I.

RESULTS AND DISCUSSION

The coefficients π_{11} and π_{44} have been measured from 77 to 350°K. The results are shown in Fig. 1. Due to the

FIG. 1. Variation of the coefficients π_{11} and π_{44} with temperature in p -type gallium antimonide. The solid line is a best fit to the experimental π_{44} data points.

small signal obtainable from transverse measurements, the coefficient π_{12} was measured only at 77 and 300°K where constant-temperature baths were used. The measured π_{12} values at 77 and 300°K are -8.0 and -2.4×10^{-12} cm²/dyn, respectively. At 300°K, π_{12} $\approx -\pi_{11}/2$, in agreement with the hydrostatic pressure results of Paul.¹¹ The π_{44} values were obtained from longitudinal measurements on [111] oriented samples

TABLE II. Values of the piezoresistance and elastoresistance* coefficients in p -type gallium antimonide at 77 and 300°K.

a The elastic constants given in Ref. 9 were used to calculate the elastoresistance values at both 77 and 300°K.

assuming $\pi_{11}+2\pi_{12}=0$. Two or more samples were measured for each orientation, and the results on different samples were found to agree within experimental error. The values of the piezoresistance and elastoresistance coefficients at 77 and 300 °K are listed in Table II.

The piezoresistance results in gallium antimonide are similar to those found in p -type germanium,⁸ indium antimonide^{12,13} and gallium arsenide¹⁴ in that the coefficient π_{44} is positive and large compared to the π_{11} and π_{12} coefficients. However, a many-valley-type band structure having energy minima along the [111] reciprocal axes could also give piezoresistance results of this symmetry.¹⁵ By combining the piezoresistance results with the previous magnetoresistance results, $3-5$ a many-valley-type band structure may be ruled out, since the magnetoresistance results require minima along the [100] reciprocal axes. The results of both measurements are consistent with a germanium-type valence band structure.

The temperature dependence of π_{44} follows very closely a *T~^l* behavior as shown in Fig. 1. This indicates that the spin-orbit splitting energy in gallium antimonide is large compared to *kT* at room temperature, since any carriers excited into the spherically symmetric split-off band would not contribute to the piezoresistance effect. The T^{-1} dependence also indicates that the gallium antimonide samples used in this investigation are not statistically degenerate, so that the magnitude of the measured piezoresistance coefficients is determined by the valence band structure.

ACKNOWLEDGMENTS

The authors wish to thank A. W. Ryberg for growing the crystals used in this investigation and Dr. Donald Long for reviewing the manuscript.

¹¹ W. Paul, J. Appl. Phys. 32, 2082 (1961).

¹² R. F. Potter, Phys. Rev. **108**, 652 (1957).
¹³ A. J. Tuzzolino, Phys. Rev. **109**, 1980 (1958).
¹⁴ M. Zerbst, Z. Naturforsch. **17a**, 649 (1962).
¹⁵ C. Herring, Bell System Tech. J. **34**, 237 (1955).